Title (en)
METROLOGY OF MULTI-LAYER STACKS

Title (de)
METROLOGIE MEHRSCHICHTIGER STAPEL

Title (fr)
MÉTROLOGIE D'EMPILEMENTS MULTICOUCHES

Publication
EP 3759423 A1 20210106 (EN)

Application
EP 19760031 A 20190227

Priority
- US 201862636419 P 20180228
- US 2019019827 W 20190227

Abstract (en)
[origin: US2019265023A1] Techniques for removing interferometry signal phase variations caused by distortion and other effects in a multi-layer stack include: providing an electronic processor sample interferometry data acquired for the stack using a low coherence imaging interferometry system; transforming, by the electronic processor, the sample interferometry data to a frequency domain; identifying a non-linear phase variation from the sample interferometry data in the frequency domain, in which the non-linear phase variation is a result of dispersion introduced into a measurement beam by the test sample; and removing the non-linear phase variation from the sample interferometry data thereby producing compensated interferometry data.

IPC 8 full level
G01B 9/02 (2006.01)

CPC (source: EP KR US)
G01B 9/02002 (2013.01 - KR); **G01B 9/02004** (2013.01 - US); **G01B 9/02007** (2013.01 - KR); **G01B 9/0201** (2013.01 - US); **G01B 9/02016** (2013.01 - EP); **G01B 9/02028** (2013.01 - US); **G01B 9/02057** (2013.01 - US); **G01B 9/02072** (2013.06 - US); **G01B 9/02074** (2013.01 - KR); **G01B 9/02075** (2013.01 - EP); **G01B 9/02084** (2013.01 - EP US); **G01B 9/0209** (2013.01 - EP); **G01B 11/026** (2013.01 - US); **G01B 11/06** (2013.01 - US); **G01B 11/0675** (2013.01 - EP); **G01B 11/14** (2013.01 - EP); **G01B 11/2441** (2013.01 - EP US); G01B 9/02057 (2013.01 - EP)

Designated contracting state (EPC)
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Designated extension state (EPC)
BA ME

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US 10591284 B2 20200317; **US 2019265023 A1 20190829**; EP 3759423 A1 20210106; EP 3759423 A4 20210428; JP 2021515218 A 20210617; JP 7174060 B2 20221117; KR 102558264 B1 20230720; KR 20200118218 A 20201014; TW 201944025 A 20191116; TW I794416 B 20230301; WO 2019168982 A1 20190906

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US 201916286833 A 20190227; EP 19760031 A 20190227; JP 2020545097 A 20190227; KR 20207027988 A 20190227; TW 108105958 A 20190222; US 2019019827 W 20190227